Climatic reliability of Electronics: Challenges and Perspectives

Seminar Program

Day 1 Thursday – 16th March 2023

08.30 – 09.00	Registration and coffee		
Session 1	Environmental issues of high pov failure mechanisms, and Testing	Environmental issues of high power/low power systems, failure mechanisms, and Testing	
09.00 – 09.30	Introduction to the seminar and Importance of Environmental Effects on Electronics as a robustness and reliability issue	Rajan Ambat Center for Electronic Corrosion, Technical University of Denmark	
09.30 – 10.00	High Humidity High Temperature and High Voltage Reverse Bias - A Required Test for Power Semiconductors in Industrial Applications	Joonas Lappanen ABB, Finland	
10.00 – 10.30	Accelerated Corrosive Gas Testing under High Voltage for Power Semiconductor Modules	Michael Hanf University of Bremen, Germany	
10.30 – 11.00	Coffee break		
Session 1 (Continued)	Environmental issues of high pov failure mechanisms, and Testing	Environmental issues of high power/low power systems, failure mechanisms, and Testing	
11.00 - 11.30	Risk Prediction of Electrochemical Migration on Electronic Control Units – A Practical Approach	Lothar Henneken Robert Bosch, Germany	
11.30 – 12.00	Paradigm shift in cooling systems: Reliability challenge in condensing application giving high RH for electronic components – a field case	John B. Jacobsen and Preben Jakobsen Grundfos, Denmark	
12.00 – 13.00	Lunch Break		

Session 1 (Continued)	Environmental issues of high power/low power systems, failure mechanisms, and Testing	
13.00 – 13.30	Insights into the microclimate in IGBT modules during lab-based wind-energy converter system tests	Christian Zorn IWES, Fraunhofer Institute, Germany
13.30 – 14.00	Improvements on film capacitor performance under climatic stress	Azahara Albendiz TDK Electronics Components, S.A.U., Spain
14.00 – 14.30	Corrosion investigations on SAC- 1Bi-xMn lead-free solder alloys	Medgyes Bálint Károly BME Budapest, Hungary
14.30 – 15.00	Passivity of tin solder alloys	Michael Schneider Fraunhofer-Institut für Keramische Technologien und System IKTS, Germany
15.00 – 15.30	Coffee break	
Session 1 (Continued)	Environmental issues of high power/low power systems, failure mechanisms, and Testing	
15.30 – 16.00	CAF Failures & High Voltage Applications	Angus Brunton Isola GmbH, Germany
16.00 – 16.30	Overcoming corrosion-related challenges of passive component integration into overmolded packages	Amar Mavinkurve NXP Semiconductors, Netherlands
16:30 – 17:00	Development of a SIR test below 5V to Characterize ECM	Graham Naisbitt Gen3systems, UK
16:30 – 17:00 17.00 – 17.15	Development of a SIR test below 5V to Characterize ECM Corrosion-related activities in the European Power Electronics Network ECPE	Graham Naisbitt Gen3systems, UK Thomas Harder European Center for Power Electronics, Germany
16:30 – 17:00 17.00 – 17.15 17:15 – 17:30	Development of a SIR test below 5V to Characterize ECM Corrosion-related activities in the European Power Electronics Network ECPE Frist day summary and bus trans location	Graham Naisbitt Gen3systems, UK Thomas Harder European Center for Power Electronics, Germany sport to the dinner

Day 2 | Friday – 17th March 2023

08.15 – 08.30	Arrival and coffee	Arrival and coffee	
Session 2	Process cleanliness effect on co optimization	Process cleanliness effect on corrosion reliability and optimization	
08.30 – 09.00	Process cleanliness and safe boundaries for PCBA humidity robustness	Rajan Ambat CELCORR, DTU, Denmark	
09.00 – 09.30	Electronic Soldering Material Reliability when exposed to Harsh Climatic Conditions	Mike Bixenman Magnalytix, USA	
09.30 – 10.00	Optical inspection and SIR measuring under the component bodies using SIR Glass Test Vehicle	Vladimír Sítko PBT Works, Czech Republic Mike Bixenman Magnalytix, USA	
10.00 – 10.30	Investigation of the effect of ionic contamination in thin gaps on assemblies close to reality with new miniaturized devices	Helge Schimanski ISIT, Fraunhofer-Institut für Siliziumtechnologie ISIT Thorsten Fladung Fraunhofer Institute for Manufacturing Technology and Advanced Materials IFAM, Germany	
10.30 – 11:00	Coffee break		
Session 2 (Continued)	Process cleanliness effect on co optimization	Process cleanliness effect on corrosion reliability and optimization	
11.00 – 11.30	Rust particles, are they able to cause shorts	Lutz Mueller, Robert Bosch, Germany	
11.30 – 12.00	An Efficient and Innovative Cleaning Solution with Low Environmental Impact	Laura LECOMTE Inventec Performance Chemical, France	
12.00 – 13.00	Lunch Break		
Session 3	Proper packaging and conformal protection from environmental e	Proper packaging and conformal coating for better protection from environmental effects	
13:00 – 13.30	Integrated climate and CFD models for humidity effects verification on electronic packaging	Max Peter Spooner, DTU-Compute & Sankhya Mohanty DTU-Construct, Denmark	

13.30 – 14:00	Humidity robustness of thermally stressed coatings	Stefan Strixner Zestron, Germany
14.00 – 14.30	UV LED conformal coating technologies	Marie Kaing ABChimie, France
14.30 – 15.00	Coffee break	
15.00 – 15.30	Plasma deposited thin halogen free conformal coating for corrosion protection of PCB	Nicolas Vandencasteele Europlasma NV, Belgium
15.30 – 16.00	Flux residue compatibility with conformal coating: Parametric study and data modelling	Ioannis Mantis CELCORR, DTU, Denmark
16:00 – 16:30	A sustainable Nanocoating technology for corrosion protection of electronics and medical devices	Rakesh Kumar Specialty Coating Systems, USA
16.30 – 16.40	Conclusion and summary	Rajan Ambat CELCORR, DTU Denmark